(19) World Intellectual Property Organization

International Bureau





(43) International Publication Date 12 September 2003 (12.09.2003)

PCT

(10) International Publication Number WO 2003/075189 A3

(51) International Patent Classification⁷: G06F 17/50

(21) International Application Number:

PCT/IB2003/000819

(22) International Filing Date: 4 March 2003 (04.03.2003)

(25) Filing Language: English

(26) Publication Language: English

(**30**) Priority Data: 10/091,934

6 March 2002 (06.03.2002) Us

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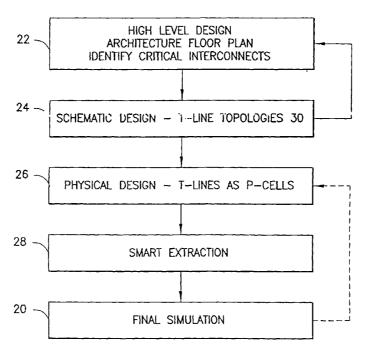
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(81) Designated States (national): AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BY, BZ, CA, CH, CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, ES, FI, GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, MZ, NO, NZ, OM, PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, TJ, TM, TN, TR, TT, TZ, UA, UG, US, UZ, VC, VN, YU, ZA, ZM, ZW.

(84) Designated States (regional): ARIPO patent (GH, GM, KE, LS, MW, MZ, SD, SL, SZ, TZ, UG, ZM, ZW), Eurasian patent (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), European patent (AT, BE, BG, CH, CY, CZ, DE, DK, EE,

[Continued on next page]

(54) Title: AN INTERCONNECT-AWARE METHODOLOGY FOR INTEGRATED CIRCUIT DESIGN



(57) Abstract: An integrated circuit design kit including one or more circuit components topologies, and one or more critical interconnect lines topologies. The interconnect line topologies may be predefined. The kit may further include one or more circuit components models and one or more critical interconnect lines models.



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ES, FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PT, RO, SE, SI, SK, TR), OAPI patent (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG).

Published:

- with international search report
- before the expiration of the time limit for amending the claims and to be republished in the event of receipt of amendments

(88) Date of publication of the international search report: 8 April 2004

For two-letter codes and other abbreviations, refer to the "Guidance Notes on Codes and Abbreviations" appearing at the beginning of each regular issue of the PCT Gazette.

			
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Electronic d	ata base consulted during the international search (name of data bas	se and, where practical, search terms used)
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C. DOCUM	ENTS CONSIDERED TO BE RELEVANT		
Category °	Citation of document, with indication, where appropriate, of the rele	evant passages	Relevant to claim No.
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X Furti	her documents are listed in the continuation of box C.	χ Patent family members are listed	in annex.
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	European Patent Office, P.B. 5818 Patentlaan 2 NL – 2280 HV Rijswijk		
	Tel. (+31-70) 340-2040, Tx. 31 651 epo nl, Fax: (+31-70) 340-3016	Alonso Nogueiro,	L

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C.(Continua	ation) DOCUMENTS CONSIDERED TO BE RELEVANT	
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FURTHER INFORMATION CONTINUED FROM PCT/ISA/ 210

Continuation of Box I.2

Claims Nos.: 1-18

A "topology" describes in the area of "wiring" a way of connecting different elements of the circuit or how to distribute signals within the circuit. Examples of topologies are a tree, a bus, a ring, a star, etc. The terms "interconnect topology" or "line topology", as used in the application refer to the structure of an interconnect line, i.e. the relative positions and sizing of several signal and shielding wires used to propagate one or more signals (see figures 3a to 3f). The terms "geometry" or "structure" seem to describe with more precision the features meant by "topology" in the application.

Claim 1: A system must be characterized in terms of structural features. It cannot be decided what kind of system could be composed of designs at different levels, extracted parameters and results of simulations. It seems that claim 1 would rather be directed to a design method like claim 19.

Claim 2: It cannot be decided what features should be searched that define a circuit design kit. A component topology and an interconnect line topology are geometrical or structural relationships between parts of the component, resp. parts of the interconnect. It is not clear how this kind of relationships may define a circuit design kit.

Claim 6: A critical interconnect line in a circuit is an interconnect line that determines the performance of the circuit (typically the one with largest delay). The toplogy of such an interconnect line is neither a step of a process nor a structural feature of a system, it is rather a mathematical, abstract description of the shape of the interconnect line.

Claims 15 and 17: A method, or a corresponding computer program, must be characterized by mehtod steps. Both claims 15 and 17 lack any feature with could be used to define them.

The applicant's attention is drawn to the fact that claims, or parts of claims, relating to inventions in respect of which no international search report has been established need not be the subject of an international preliminary examination (Rule 66.1(e) PCT). The applicant is advised that the EPO policy when acting as an International Preliminary Examining Authority is normally not to carry out a preliminary examination on matter which has not been searched. This is the case irrespective of whether or not the claims are amended following receipt of the search report or during any Chapter II procedure.

Box I Observations where certain claims were found unsearchable (Continuation of item 1 of first sheet)
This International Search Report has not been established in respect of certain claims under Article 17(2)(a) for the following reasons:
Claims Nos.: because they relate to subject matter not required to be searched by this Authority, namely:
2. X Claims Nos.: 1-18 because they relate to parts of the International Application that do not comply with the prescribed requirements to such an extent that no meaningful International Search can be carried out, specifically:
see FURTHER INFORMATION sheet PCT/ISA/210
3. Claims Nos.: because they are dependent claims and are not drafted in accordance with the second and third sentences of Rule 6.4(a).
Box II Observations where unity of invention is lacking (Continuation of item 2 of first sheet)
This International Searching Authority found multiple inventions in this international application, as follows:
1. As all required additional search fees were timely paid by the applicant, this International Search Report covers all searchable claims.
2. As all searchable claims could be searched without effort justifying an additional fee, this Authority did not invite payment of any additional fee.
3. As only some of the required additional search fees were timely paid by the applicant, this International Search Report covers only those claims for which fees were paid, specifically claims Nos.:
4. No required additional search fees were timely paid by the applicant. Consequently, this International Search Report is restricted to the invention first mentioned in the claims; it is covered by claims Nos.:
Remark on Protest The additional search fees were accompanied by the applicant's protest. No protest accompanied the payment of additional search fees.

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